
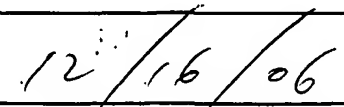


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 728-235 (YOR9-2003-0122-US)		SERIAL NO. 10/620,247	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (Use several sheets if necessary)				APPLICANTS Arun Hampapur et al.			
				FILING DATE July 15, 2003		GROUP ART UNIT 2613	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES      NO
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
CA		1.	Peixoto, Batista and Araujo, "A Surveillance System Combining Peripheral and Foveated Motion Tracking," ICPR, 1998				
		2.	Collins, Lipton, Fujiyoshi, and Kanade, "Algorithms for cooperative multisensor surveillance," Proc. IEEE, Vol. 89, No. 10, Oct. 2001				
EP		3.	Stillman, Tanawongsuwan and Essa, "A System for Tracking and Recognizing Multiple People with Multiple Cameras," Georgia TR# GIT-GWU-98-25, August 1998				
		4.	"FaceIt" a commercially available package from Identix Corporation found on the Internet at <a href="http://www.identix.com/">http://www.identix.com/</a>				
SP		5.	"Appearance Models for Occlusion Handling" by Andrew Senior, Arun Hampapur, Ying-Li Tian, Lisa Brown, Sharath Pankanti and Ruud Bolle published in <i>Proceedings 2nd IEEE Int. Workshop on PETS, Kauai, Hawaii, USA, in December 9 2001</i>				
		6.	Haritaoglu, D. Harwood, and L. S. Davis. W4: Real-time surveillance of people and their activities. <i>IEEE Trans. Pattern Analysis and Machine Intelligence</i> , 22(8): 809-830, August 2000				
SP		7.	"Face Cataloger: Multi-Scale Imaging for Relating Identity to Location" by Arun Hampapur, Sharath Pankanti, Andrew Senior, Ying-Li Tian, Lisa Brown, Ruud Bolle, to appear in IEEE Conf. on Advanced Video and Signal based Surveillance Systems, 20-22 July 2003, Miami FL				
		8.	Comanicui D, Ramesh V and Meer P, Real Time Tracking of Non-Rigid Objects using Mean Shift, IEEE Conf on Computer Vision and Pattern Recognition, Vol. II, 2000, pp 142-149				
EXAMINER				DATE CONSIDERED			
							
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							